

Notice of References Cited			Application/Control No. 10/579,492	Applicant(s)/Patent Under Reexamination HAARER ET AL.	
			Examiner Gail Verbitsky	Art Unit 2855	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2005/0139686	06-2005	Helmer et al.	235/494
*	B US-5,667,303	09-1997	Arens et al.	374/102
*	C US-2005/0037498	02-2005	Ribi, Hans O.	436/002
*	D US-7,263,501	08-2007	Tirinato et al.	705/28
*	E US-2003/0139843	07-2003	Hu et al.	700/211
*	F US-2005/0178841	08-2005	Jones et al.	235/468
*	G US-4,859,360	08-1989	Suzuki et al.	252/299.7
*	H US-7,263,501	08-2007	Tirinato et al.	705/28
*	I US-2004/0182932	09-2004	Kawai, Hiroaki	235/462.15
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 10046072 A	02-1998	Japan	TONOMURA et al.	
O	JP 10334171 A	12-1998	Japan	OKADA, MINORU	
P	WO 9427242 A1	11-1994	World Intellect	NISHIDA et al.	
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.